

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In reApplication of: Rajski et al.

Application No. 09/620,021

Filed: July 20, 2000

For: CONTINUOUS APPLICATION AND

DECOMPRESSION OF TEST PATTERNS TO A

CIRCUIT-UNDER-TEST Examiner: Phung M. Chung

Date: January 3, 2003

Art Unit: 2133

## **CERTIFICATE OF MAILING**

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service on January 3, 2003 as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, WASHINGTQN, D.C. 20231.

Robert F. Scotti Attorney for Applicant

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COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

## **AMENDMENT**

Responsive to the Office action dated October 03, 2002, Paper No. 9, please amend the subject application as follows:

In the Claims:

Please add new claims 39-47 as follows:

39. (New) The method of claim 1 wherein the compressed test pattern is provided to a decompressor while the decompressor is decompressing the compressed test pattern.

- 40. (New) The method of claim 1 wherein the compressed test pattern is provided by automated test equipment while a decompressor is decompressing the compressed test pattern.
- 41. (New) The method of claim 1 further including loading an intermediate register with the compressed test pattern, the intermediate register positioned between a decompressor, which is performing the decompressing and automated test equipment which is providing the compressed test pattern.

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